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Enhanced and Synthetic Vision 2009

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Introduction

This is the 15th volume of the series of conferences on Enhanced and Synthetic Vision.

After the first two proceedings volumes numbered 2220 (in 1994) and 2463 (in 1995), the proceedings volumes were systematically titled "Enhanced and Synthetic Vision YEAR," where YEAR stands for the year the conference was held: Proceedings of SPIE Vols. 2736 (1996), 3088 (1997), 3364 (1998), 3691 (1999), 4023 (2000), 4363 (2001), 4713 (2002), 5081 (2003), 5424 (2004), 5802 (2005), 6226 (2006), 6559 (2007), and 6957 (2008).

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